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ABSTRACT OF THE DISCLOSURE

A circuit that may be used to implement boundary scan The circuit generally comprises a pad circuit, a core testing. The pad circuit may be logic, a cell, and a test circuit. configured to transfer a data signal in response to a pad control signal. The core logic may be configured to (i) exchange the data signal with the pad circuit and (ii) present a control signal. cell may be configured to (i) transfer the data signal between the pad circuit and the core logic and (ii) swap the data signal and a test signal. The test circuit may be configured to (i) exchange 10 (the test data signal with the cell, (ii) store a test control signal, and (iii) multiplex the test control signal and the control signal to present the pad control signal.